

Model : EC-80

Non-Contact (Eddy Current method)
sheet resistance/resistivity measurement equipment
Manual type (1 point measurement type)



Simply measurement is realized put the samples on the stage.
You can measure the resistivity without any sample damage.

Features

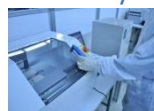
- There is upper probe and lower probe in the measurement position on the stage.
- Easy measurement setting by JOG dial.
- Easy measurement mode change between sheet resistance and resistivity by JOG dial.
- Wide measurement range by using LOW/MIDDLE/HIGH/SUPER HIGH probes.
- **※EC-80 can mount one probe only.**
- Probe core diameter : 14mm Φ
- Temperature correction (For silicon wafer)

Applications

- Wafer sample ;
Silicon bare, Compound(GaN, GaP), Epitaxial, Diffusion, SiC etc...
 - Thin film layer ;
Semiconductor process, Metal film, ITO film etc...
 - Others
- *Generally, it will be able to measure the resistivity and sheet resistance in measurement range.

Sample size

2~8 inch or up to 156×156mm
Corresponding sample thickness is 300~800um



Measurement Range

* You need to choose a probe from below measurement range.

Probe Type	Measurement Range
(1) Low	0.01 - 0.5 ohm/sq (0.0005 - 0.025 ohm.cm)
(2) Middle	0.5 - 10 ohm/sq (0.025 - 0.5 ohm.cm)
(3) High	10 - 1000 ohm/sq (0.5 - 50 ohm.cm)
(4) Super High	1000 - 3000 ohm/sq (50 - 150 ohm.cm)

*Resistivity range for each probe type(ohm.cm) assumed thickness : 500μm.

* Resistivity is a reference value due to variations with sample thickness.

Measurement Repeatability

Measurement Range	%
Low, Middle	≦ 0.7 %
High	≦ 1.0 %
Super High	≦ 3.0 %

*Measurement Repeatability : $CV = \frac{STDEV}{AVG} \times 100\%$

(It is repeatedly measured by 10 times on same position using NIST and VLSI standard wafers.)

*Above dates are based on the measurement of standard wafers before product shipment.

Dimensions & Utilities

<Dimensions> Main body : W220 × D325 × H210mm 6.5kg

<Utilities> AC100V±10%, 50/60Hz, 100VA

- Please contact us if you want more details.
- We can correspond the demo measurement by your samples if you want it.
- The specification subject to change without any notice.